Probe Software

Software for MicroAnalysis

Probe for EPMA

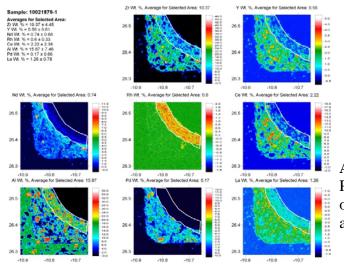
Probe Image

PictureSnapApp

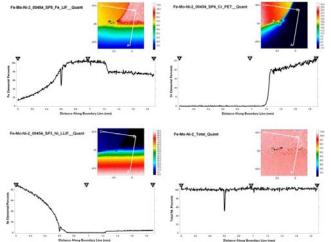
Probe Image Quantitative X-ray Mapping

Probe Image for Background, Matrix and Interference Corrected Quantitative X-ray Mapping

Based on optimized C++ code for robust, high speed operation, Probe Image provides a complete solution for manual and automated analog signal (SE, BSE, CL, etc.) imaging, and x-ray (WDS and EDS) mapping of multiple samples under multiple conditions for JEOL and Cameca EPMA instruments.



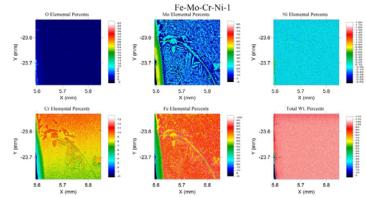
easily save and recall previous acquisition setups. All data is saved with 32 bit floating point precision to ensure that all digital intensities are preserved with maximum flexibility for subsequent qualitative or quantitative post-processing including total and oxygen by stoichiometry images.



Acquisition Samples					Sample Parameters				/ State 2Pt X Position 21.4217 Basel X V					Controls	
	Sample N	lame	Time		O Beam		Stage Ctr	() Step				4232	Read X,V	Read A	
	53-34		00h 58m 58	6	Pixel		3	(msec)		V Positi		3200		Move	
1 00	100		gon see si		Imag	e Size	256 x 256	(pixets)		2 Positi		1230	Read Z	Movel	
					Enable	Offpeak P	esitive	30	(miec)	Magnificat Pixel 5		978	Read	Movel	
					Enable	Offpeak N	legative	30	(msec)	Scan 1		-	(um)	Movel	
1000	Before Ince												et. 1	Movel	
(prosect)	Defore June	A AGE	Deleta												
nput Channel	×														
WDS Inputs	EDS Inputs	Analog Ing	puts Column	Condition	6										
WDSL															
(2) Enable	Bernent	9	XRayLine	• •	Crystal	PET +	Pesition	228.095	- Offset	4.420	- Offset	-4.4	III Rea	H ELM	
PHA	Baseline	1.00	Wedow	9.00	Gein	32	Bies	1674	Mode	Integral +	Deathine		0 Res	ed level.	
W052															
(2) Enable	Bernert	fe	XRay Line 1		Crystal	- HR	Pesition	134.723	- Offset	3.927	- Offset	-3.9	127 Rea	d ELM	
PHA	Eeseline	1.00	Window	9.00	Gain	36	Bies	1764	Mode	Integral +	Deathine		0 Res	ed level.	
W053															
12 Evable	Bernert	Ce .	XRay Line		Crystal	PET .	Position	107.523	- Offset	9.636	- Offset	-94	35 Rea	ed ELM	
PHA	a Baseline	0.30	Window	9.70	Gain	32	fier	1750	Mode	Integral +	Deathine		0 Res	ed level.	
WD54															
(2) Enable	Dement	-51	XRay Line		Crystal	PET .	Pesition	228.073	+ Offset	4.410	- Offset	-4.4	III Rea	Read ELM	
PHA	& Baseline	2.00	Window	8.00	Gein	64	6ies	1650	Mode	Integral +	Deattime		0 Res	ed level.	
WDS5															
Enable	Dement	Ti -	XRay Line	•	Crystal	UF •	Position	191.218	- Office	3,719	- Offset	-3.3	19 Res	NI ELM	
РНА	k Baseline	0.45	Window	9.35	Gein	15	Bies	1790	Mode	Integral +	Deadtime		0 Res	ed Inst.	

Automated Peak and Background Acquisition

Probe Image provides an intuitive interface for specification of all imaging and mapping acquisition parameters. Select all acquisition and automation options in a single window and



Complete Quantification and Output

Probe Image utilizes quantification based on Probe for EPMA for correction of background (off-peak or modeled), matrix (analytical or high speed monte-carlo) and interference corrections and provides numerous automated outputs for generation of presentation quality reports including slice, strip and polygon area extraction.

Probe Software, Inc. 885 Crest Drive Eugene, OR 97405 USA (541) 343-3400 sales@probesoftware.com www.probesoftware.com

